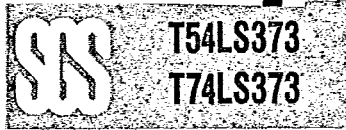


# LOW POWER SCHOTTKY INTEGRATED CIRCUITS



67C 16458

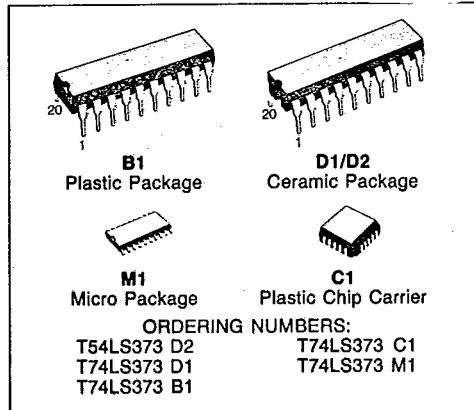
D

T-46-07-11

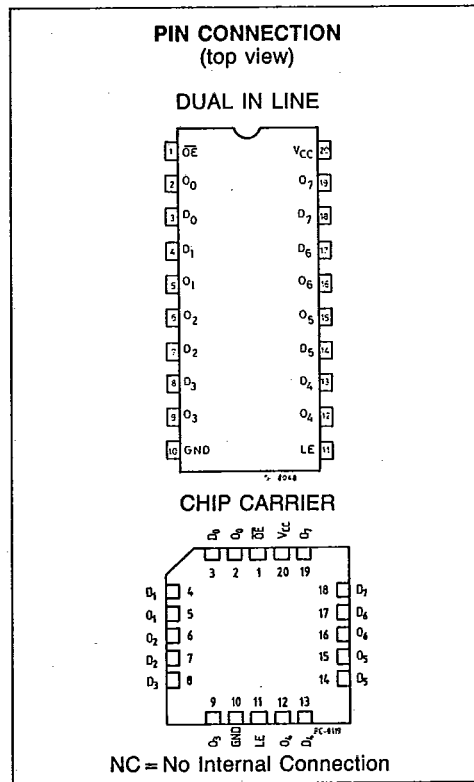
## OCTAL TRANSPARENT LATCH WITH 3-STATE OUTPUTS

### DESCRIPTION

The T54LS373/T74LS373 consists of eight latches with 3-state outputs for bus organized system applications. The flip-flops appear transparent to the data (data changes asynchronously) when Latch Enable (LE) is HIGH. When LE is LOW, the data that meets the set-up times is latched. Data appears on the bus when the Output Enable ( $\overline{OE}$ ) is LOW. When  $\overline{OE}$  is HIGH the bus outputs is in the high impedance state.

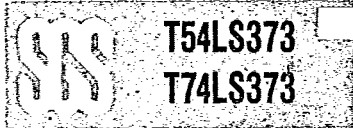


- EIGHT LATCHES IN A SINGLE PACKAGE
- 3-STATE OUTPUTS FOR BUS INTERFACING
- HYSTERESIS ON LATCH ENABLE
- INPUT CLAMP DIODES LIMIT HIGH SPEED TERMINATION EFFECTS
- FULLY TTL AND CMOS COMPATIBLE

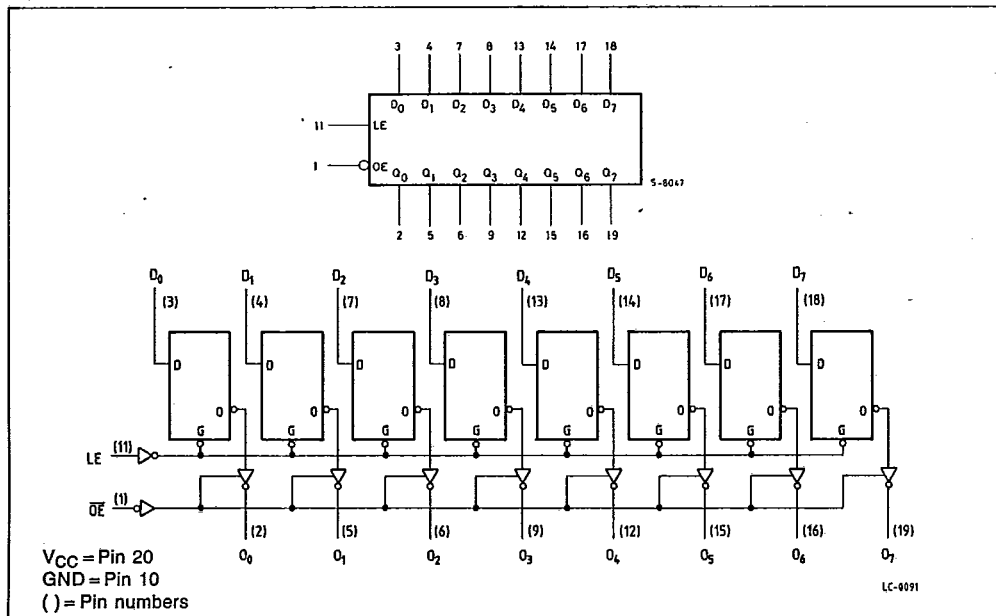


### PIN NAMES

D <sub>0</sub> -D <sub>7</sub>	Data Inputs
LE	Latch Enable (Active HIGH) Input
$\overline{OE}$	Output Enable (Active LOW) Input
O <sub>0</sub> -O <sub>7</sub>	Outputs



**LOGIC SYMBOL AND LOGIC DIAGRAM**



**ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply Voltage	-0.5 to 7	V
V <sub>I</sub>	Input Voltage, Applied to Input	-0.5 to 15	V
V <sub>O</sub>	Output Voltage, Applied to Output	-0.5 to 10	V
I <sub>I</sub>	Input Current, Into Inputs	-30 to 5	mA
I <sub>O</sub>	Output Current, Into Outputs	50	mA

Stresses in excess of those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions in excess of those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

**GUARANTEED OPERATING RANGES**

Part Numbers	Supply Voltage			Temperature
	Min	Typ	Max	
T54LS373D2	4.5 V	5.0 V	5.5 V	-55°C to +125°C
T74LS373XX	4.75 V	5.0 V	5.25 V	0°C to +70°C

XX = package type.



T54LS373

T74LS373

## DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE

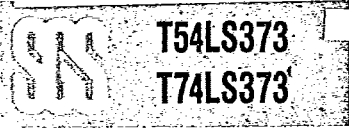
Symbol	Parameter		Limits			Test Conditions (Note 1)	Units	
			Min.	Typ.	Max.			
V <sub>IH</sub>	Input HIGH Voltage		2.0			Guaranteed input HIGH Voltage for all Inputs	V	
V <sub>IL</sub>	Input LOW Voltage	54		0.7		Guaranteed input LOW Voltage for all Inputs	V	
		74		0.8				
V <sub>CD</sub>	Input Clamp Diode Voltage			-0.65	-1.5	V <sub>CC</sub> = MIN, I <sub>IN</sub> = -18mA	V	
V <sub>OH</sub>	Output HIGH Voltage	54	2.4	3.4		I <sub>OH</sub> = 0.1mA I <sub>OL</sub> = 2.6mA	V <sub>CC</sub> = MIN, V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub> per truth table	V
		74	2.4	3.1				
V <sub>OL</sub>	Output LOW Voltage	54,74		0.25	0.4	I <sub>OL</sub> = 12mA I <sub>OL</sub> = 24mA	V <sub>CC</sub> = MIN, V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub> per truth table	V
		74		0.35	0.5			
I <sub>OZH</sub>	Output Off Current HIGH				20	V <sub>CC</sub> = MAX, V <sub>OUT</sub> = 2.4V, V <sub>E</sub> = 2.0V	μA	
I <sub>OZL</sub>	Output Off Current LOW				-20	V <sub>CC</sub> = MAX, V <sub>OUT</sub> = 0.4V, V <sub>E</sub> = 2.0V	μA	
I <sub>IH</sub>	Input HIGH Current				20	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 2.7V	μA	
	Input HIGH Current at MAX Input Voltage				0.1	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 7.0V	mA	
I <sub>IL</sub>	Input LOW Current				-0.4	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 0.4V	mA	
I <sub>OS</sub>	Output Short Circuit Current (Note 2)		-30		-130	V <sub>CC</sub> = MAX, V <sub>OUT</sub> = 0V	mA	
I <sub>CC</sub>	Power Supply Current Outputs Off			24	40	V <sub>CC</sub> = MAX, V <sub>IN</sub> = 0V, V <sub>E</sub> = 4.5V	mA	

AC CHARACTERISTICS: (T<sub>A</sub> = 25°C)

Symbol	Parameter		Limits			Test Conditions	Units	
			Min.	Typ.	Max.			
t <sub>PLH</sub>	Propagation Delay, Data to Output			12	18	Fig. 1	C <sub>L</sub> = 15pF	ns
t <sub>PHL</sub>				12	18			
t <sub>PLH</sub>	Propagation Delay, Clock or LE to Output			20	30	Fig. 1	C <sub>L</sub> = 15pF	ns
t <sub>PHL</sub>				18	30			
t <sub>PZH</sub>	Output Enable Time to HIGH Level			15	28	Figs. 3,4	C <sub>L</sub> = 15pF R <sub>L</sub> = 2 kΩ	ns
t <sub>PZL</sub>	Output Enable Time to LOW Level			25	36	Figs. 2,4		
t <sub>PLZ</sub>	Output Disable Time from LOW Level			15	25	Figs. 2,4	C <sub>L</sub> = 5pF R <sub>L</sub> = 2 kΩ	ns
t <sub>PHZ</sub>	Output Disable Time from HIGH Level			12	20	Figs. 3,4		

## Notes:

- 1) Conditions for testing, not shown in the Table, are chosen to guarantee operation under "worst case" conditions.
- 2) Not more than one output should be shorted at a time.
- 3) Typical values are at V<sub>CC</sub> = 5.0V, T<sub>A</sub> = 25°C



**AC SET-UP REQUIREMENTS:  $T_A = 25^\circ\text{C}$**

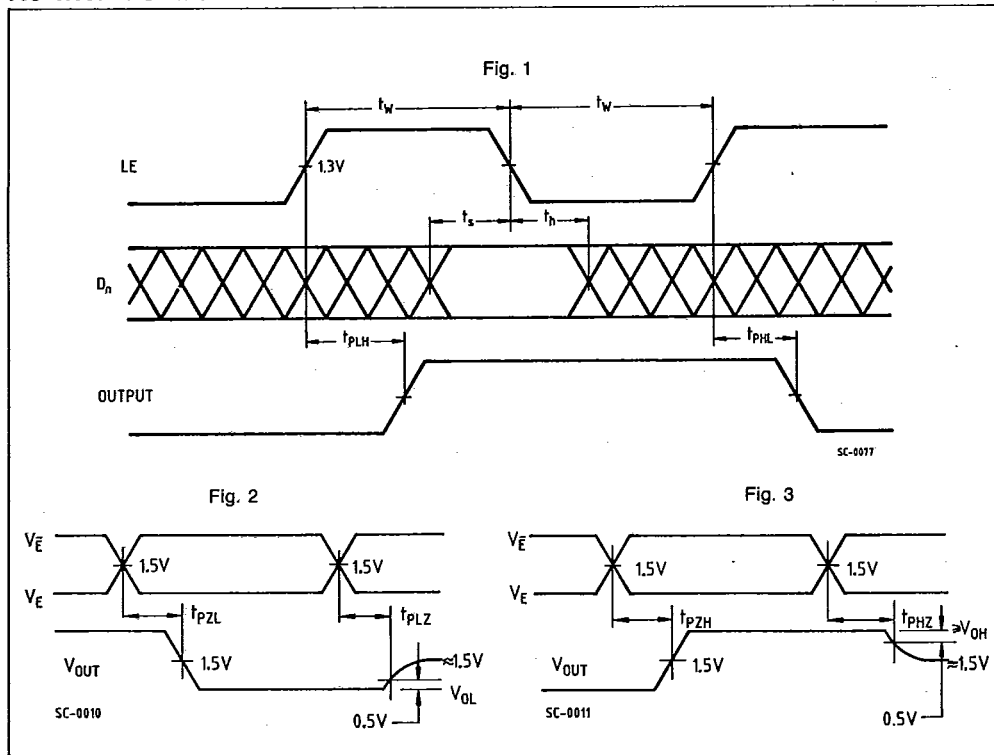
Symbol	Parameter	Limits			Test Conditions	Units
		Min.	Typ.	Max.		
$t_{sD}$	Set-up Time Data to Negative Going LE	20	11		Fig. 1 $V_{CC} = 5.0\text{V}$	ns
$t_{hD}$	Hold Time Data to Negative Going LE	20	11			ns
$t_{wLE}$	Minimum LE Pulse Width HIGH to LOW	15	10			ns

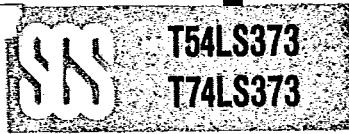
**DEFINITION OF TERMS:**

SET-UP TIME ( $t_s$ ) - is defined as the minimum time required for the correct logic level to be present at the logic input to LE transition from HIGH to LOW in order to be recognized and transferred to the outputs.

HOLD TIME ( $t_h$ ) - is defined as the minimum time following LE transition from LOW to HIGH that the logic level must be maintained at the input in order to ensure continued recognition.

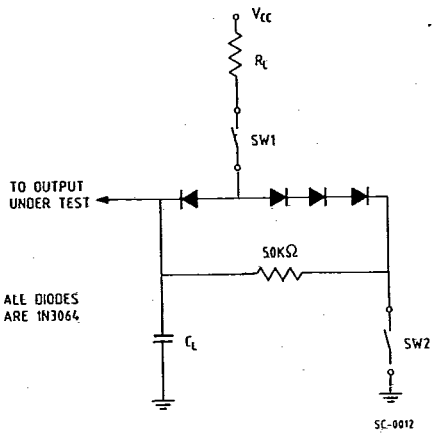
**AC WAVEFORMS**





AC LOAD CIRCUIT

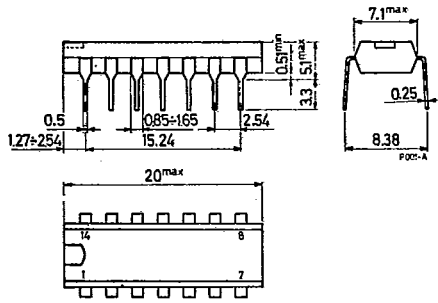
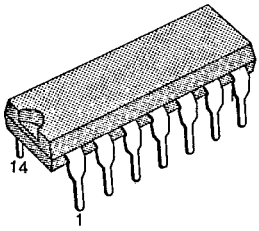
Fig. 4



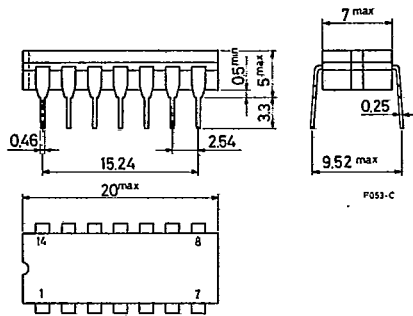
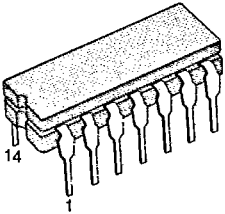
SWITCHING POSITIONS

Symbol	SW1	SW2
tpZH	Open	Closed
tpZL	Closed	Open
tpLZ	Closed	Closed
tpHZ	Closed	Closed

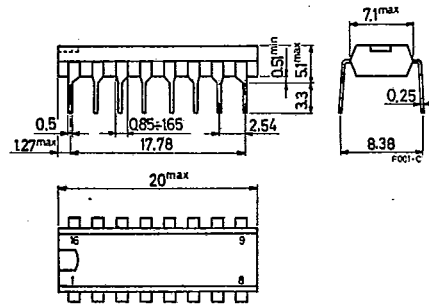
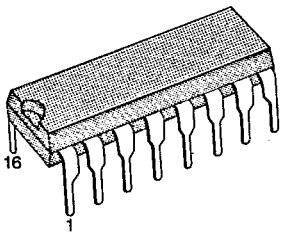
14-LEAD PLASTIC DIP



14-LEAD CERAMIC DIP



16-LEAD PLASTIC DIP



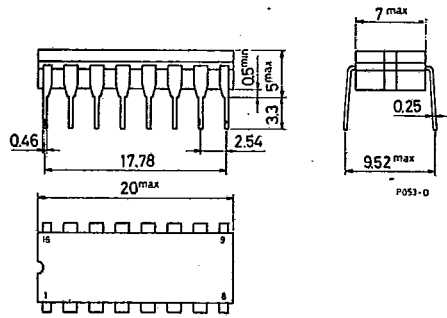
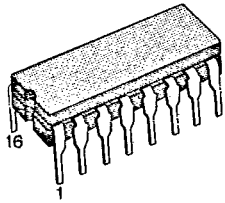
# Packages

67C 16545

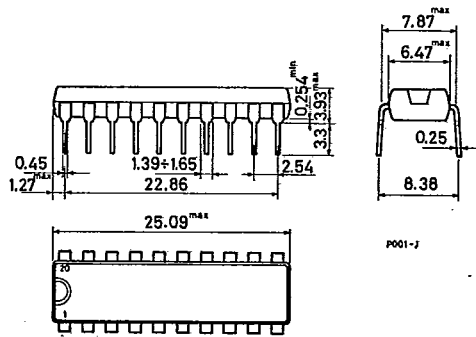
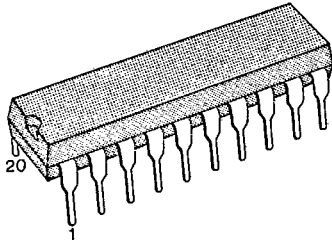
D

T-90-20

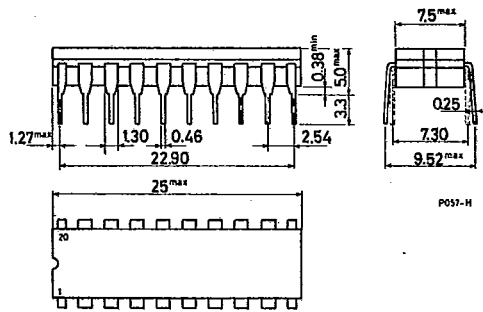
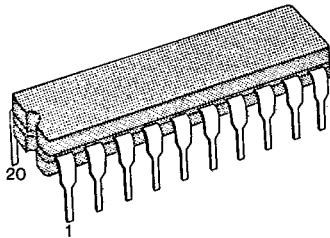
## 16-LEAD CERAMIC DIP



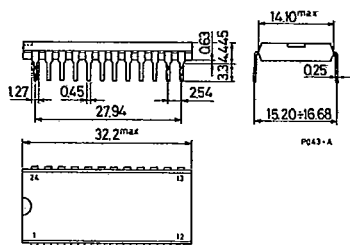
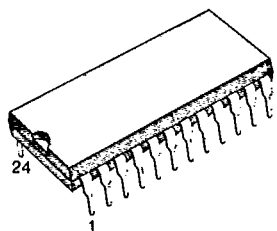
## 20-LEAD PLASTIC DIP



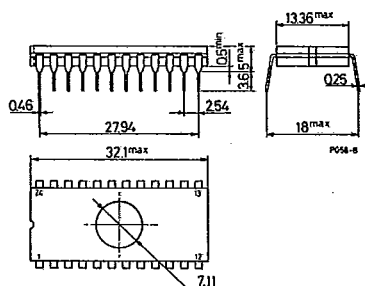
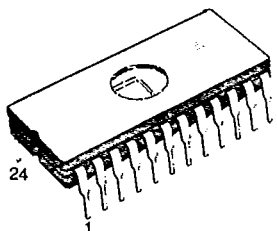
## 20-LEAD CERAMIC DIP



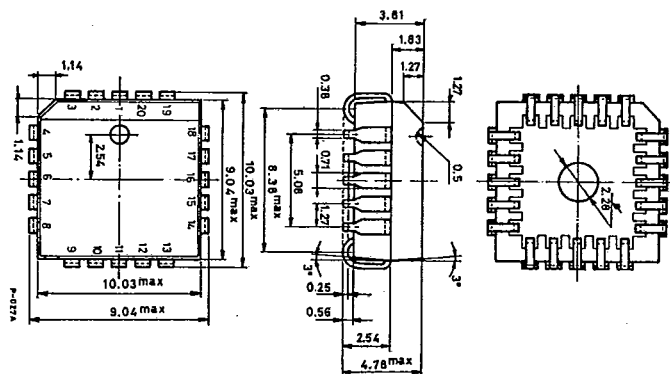
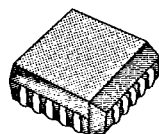
### 24-LEAD PLASTIC DIP



### 24-LEAD CERAMIC DIP



### CHIP CARRIER 20 LEAD PLASTIC





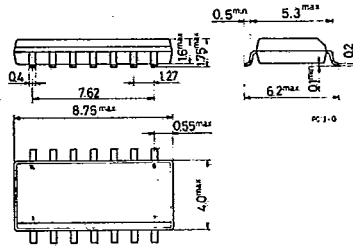
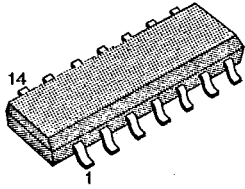
# Packages

67C 16547

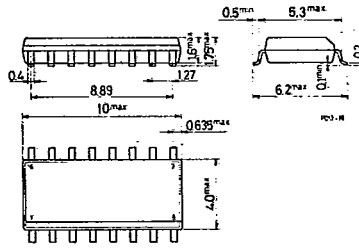
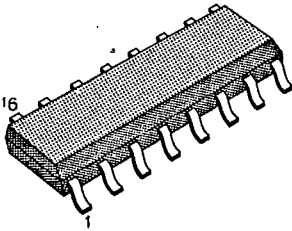
D

T-90-20

## 14-LEAD PLASTIC DIP MICROPACKAGE



## 16-LEAD PLASTIC DIP MICROPACKAGE



NOTE: FOR 20-LEAD PLASTIC DIP MICROPACKAGE CONTACT SGS

# Surface Mounted

67C 16548

D

T-90-20

One possible solution to the important problem of PWB minimization, is that of using surface mounted components. Integrated circuits in SO (Small Outline) packages are made up of standard chips mounted in very small plastic packages. The advantages given by using these devices are:

## PWB Reduction

This is by far the most important advantage since the reduction of PWB size varies from 40 to 60% in comparison with standard board types. (See page 584 for package dimensions.)

## Assembly Cost Reduction

SO Devices require no preliminary operation prior to mounting and can therefore be easily utilized in fully automatic equipment.

## Increasing Reliability

The following characteristics lead to a higher level of reliability with respect to their standard packaged counter parts:

- The mounting system is fully automatic
- PWB number and the interconnections between them are reduced when the same number of devices are used.
- The high density of components on the board makes it thermally much more stable.

## Noise Reduction and Improved Frequency Response

The reduction of the length of the connecting wires between the leads and the silicon guarantees a more homogeneous propagation delay between the external pins, with respect to the standard type.

## Assembly Without Board Holes

The devices are placed on the board and soldered. This technology permits a higher level of tolerance in the positioning (automatic) of the device. For the standard DIP types this must be done with great accuracy due to the insertion of the leads into their holes.

